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|-----------------------------------|---------------------------------------|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/709,361 | Applicant(s)/Patent Under<br>Reexamination<br>FOREMAN ET AL. |             |
|                                   | Examiner<br>Toan M. Le                | Art Unit<br>2863   | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                 | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,912,665                                     | 06-2005         | Ellis et al.         | 713/401        |
| * | B | US-6,658,635                                     | 12-2003         | Tanimoto, Tadaaki    | 716/6          |
| * | C | US-6,253,359                                     | 06-2001         | Cano et al.          | 716/6          |
| * | D | US-5,654,898                                     | 08-1997         | Roetcisoender et al. | 716/9          |
| * | E | US-5,508,937                                     | 04-1996         | Abato et al.         | 716/6          |
| * | F | US-6,148,434                                     | 11-2000         | Nozuyama, Yasuyuki   | 716/6          |
| * | G | US-5,764,525                                     | 06-1998         | Mahmood et al.       | 716/18         |
| * | H | US-5,426,591                                     | 06-1995         | Ginetti et al.       | 716/6          |
| * | I | US-5,944,834                                     | 08-1999         | Hathaway, David J.   | 713/500        |
| * | J | US-6,615,395                                     | 09-2003         | Hathaway et al.      | 716/6          |
| * | K | US-2005/0066297                                  | 03-2005         | Kalafala et al.      | 716/006        |
|   | L | US-  |                 |                      |                |
|   | M | US-  |                 |                      |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)                   |
|---|---|---|
| X | U | Orshansky et al., A General Probabilistic Framework for Worst Case Timing Analysis, DAC 2002, Pages 556-561 |
|   | V |   |
|   | W |   |
|   | X |   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.